

INSPECTION METHOD FOR ARRAY SUBSTRATE
AND INSPECTION DEVICE FOR THE SAME

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ABSTRACT OF THE DISCLOSURE

Disclosed are an inspection method for a disconnection of a storage capacitor line and an inspection device for the same in an inspection of an array substrate used in a liquid crystal display apparatus. An inspection method for an array substrate is constituted, in which a quantity of charges stored in the storage capacitor becomes $C(V_{d1} - V_{cs1})$ by supplying simultaneously a pulse signal V_d and a pulse signal V_{cs} to the storage capacitor from a signal line and a C_s line on a TFT array substrate, and an influence of the disconnection of the C_s line is taken into consideration when the above-described quantity of charges is detected in a reading circuit. Note that the above-described inspection is performed not for all the storage capacitors, but for one storage capacitor in each C_s line. Thus, the inspection for all the C_s lines in liquid crystal panels from 14 inch diagonal to 18 inch diagonal is terminated in about 1 to 2 seconds.

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